

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/628,058	LEE ET AL.
	Examiner	Art Unit
	Huyen X. Vo	2626

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
704	223; 217	7/22/2008	HV
704	216; 218	7/22/2008	HV
704	224; 219	7/22/2008	HV